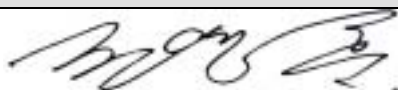


EMC Test Report

According to FCC Part 15 Subpart B

Project No.	LBE041294
Equipment under Test	
Applicant	Samsung Electronics Co. Ltd 416 Maetan-3 Dong, Yeoung tong-Ku, Suwon City, Gyeonggi-Do, Korea, 442-742
FCC ID	A3LSECSMOM
Product Name	USB Flash Drive
Model Name	SECSMOM_1G
Manufacturer	Samsung Electronics Co. Ltd
Date of Test	June 30, 2004 ~ July 03, 2004
Issued Date	July 10, 2004

	Name/Position	Signature
Tested by	Young Hun, Cheong Test Engineer	
Reviewed by	No Cheon, Park Manager of EMC Lab.	
Authorized by	Kyu Baek, Chung Chief of EMC Lab.	

1. This test reports does not constitute an endorsement by NIST/NVLAP or U.S Government.
2. This test report is to certify that the tested device properly complies with the requirements of FCC Rules and Regulations Part 15 Subpart B Unintentional Radiators.

All tests necessary to show compliance to the requirements were and these results met the specifications requirement.

This laboratory is registered by the NIST/NVLAP, U.S.A.

The test reported herein have been performed in accordance with its terms of registration.



NVLAP LAB CODE 200623-0

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1. General Information

1.1 Basic Information related Product

Applicant	Samsung Electronics Co. Ltd.
Model name	SECSMOM_1G
Applicant Address	Samsung Electronics Co. Ltd; 416 Maetan3- Dong, Yeoung tong-Ku, Suwon City, Gyeonggi-Do, Korea, 443-742
Contact Person	Young Hun, Cheong
Kind of product	USB Flash Drive
Valiant list	512MB : SECSMOM_512 256MB : SECSMOM_256 128MB : SECSMOM_128 64MB : SECSMOM_64 32MB : SECSMOM_32 16MB : SECSMOM_16
Manufacturer	Samsung Electronics Co.Ltd.
New / Alternative / Permissive change Information	New

1.2 Detail Information related Product

Specification

Item	Specification	Remark
USB Flash Drive	- Fully compatible with the USB 2.0 High speed Specification , USB-IF certified - USB Specification V1.1 Mass Storage Compliance - USB Bulk Only Mass Storage Support - USB Class Definition for Bootability Support - Interface Speed : up to - High Speed : 480M bps - Full Speed : 12M bps - High Performance : Sequential Read/Write : 15MB/s (Max.) - Storage Capacities : Up to 1GB - Software support : - Password lock - Secure zoning - Auto Sleep Mode - USB Bus Powered (4.75 volt – 5.25 volt) - Suspend ≤ 500uA	

Operating Frequency

Crystal : 12MHz(Ceramic SMD-type)

1.3 Operating Mode and Condition

The EUT exercise program used during radiated and conducted testing was designed to exercise the various system components in a manner similar to typical use.

So we used windows media player program, It operated read continuously on EUT.

The system was tested with the configuration of clause 1.4.

In each test mode, Finally we found worst case emission that is above configuration with 'the Worst case components(in the above table). So, the DATA of the maximum EUT operation was reported.

Further details of cabling and configuration are shown in the test system configuration.

1.4 Test System Details

Refer to 1.2

1.5 Equipment Modifications

No equipment modifications were required.

1.6 Test Procedure

1.6.1 Disturbance Voltage at Mains

EUT was placed on a platform nominal size, 1m by 1.5m, raised 80cm above the conducting ground plane. The rear of tabletop was located 40cm to the vertical conducting ground plane.

The rear of EUT, including peripherals was aligned and flush with rear of tabletop.

All other surfaces of tabletop was at least 80cm from any other grounded conducting surface. I/O cables and AC cables that were connected to the peripherals were bundled in center. They were folded back and forth forming a bundle 30cm to 40cm long and were hanged at a 40cm height to the ground plane.

Each EUT current-carrying power lead, except the ground(safety)lead, were individually connected through a LISN to the input power source.

All unused 50 ohm connectors of the LISN were resistively terminated in 50 ohm when not connected to the measuring equipment.

1.6.2 Radiated disturbance

EUT was placed on a platform of nominal size, 1m by 1.5m, raised 80cm above the conducting ground plane.

The rear of EUT, including peripherals was aligned and flush with rear of tabletop.

I/O cables that were connected to the peripherals were bundle in center.

They were folded back and forth forming a bundle 30cm to 40cm long and were hanged 40cm height to the ground plane.

Test was made with the antenna positioned in both the horizontal and vertical planes of polarization. The measurement antenna was varied in height above the conducting ground plane and the run table azimuth was varied to obtain the maximum signal strength

The system configuration, clock speed, mode of operation or video resolution, turntable azimuth with respect to the antenna were noted for each frequency found.

The spectrum was scanned from 30 to 1000 MHz using biconiLog antenna.

1.7 Test Configuration

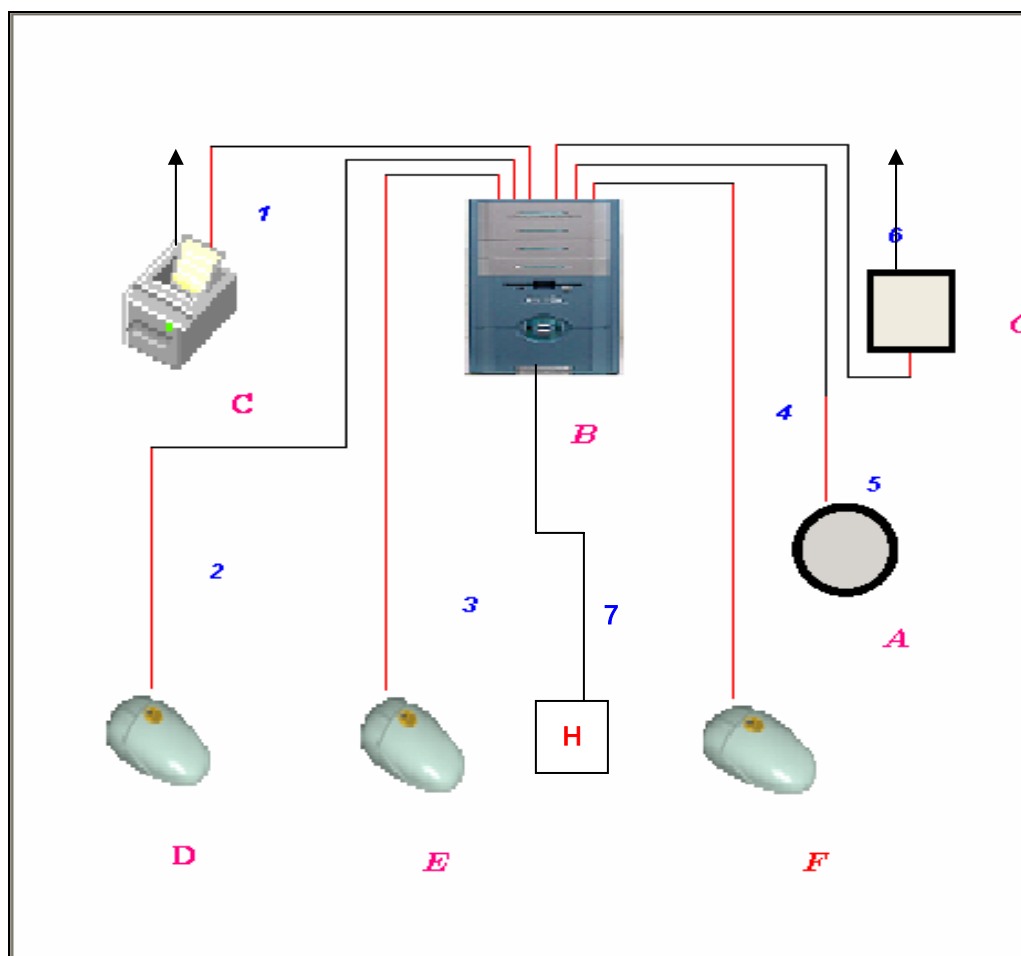
Used EUT and Peripherals

Seq	Device	Model Name	Serial #	Maker	Note
A	USB Flash Drive	SECSMOM_1G	-	SAMSUNG	EUT
B	NOTE PC	BLADE	-	DELL	DOC
C	DESKJET PRINTER	LQ-580H	CG2Y014508	EPSON	DOC
D	USB MOUSE	M-UV69a	HCA40801485	LOGITECH	DOC
E	SERIAL MOUSE	C3KMS1	1020764	MICRO SOFT	C3KMS1
F	PS/2 MOUSE	SCROLL MOUSE P801	02161489	LOGITECH	DOC
G	AC ADAPTOR	PA-1500-05D	DDR334-48010-286-00E0	DELL	-

Used Cable Description

	Connect Cable	Length [m]	Shielded [Y/N]	Remark
1	Parallel Cable	1.8	Yes	For Printer
2	USB Cable	1.6	Yes	For Mouse
3	Serial Cable	1.6	Yes	For Mouse
4	PS/2 Cable	1.8	No	For Mouse
5	Card Reader Cable	1.6	Yes	For Card Reader
6	AC Power Cable	1.7	No	For AC Adaptor
7	Earphone Cable	1.5	No	For Earphone

Block Diagram



1.8 Applied Standards

List

Product or Generic Standards	Basic Standards
FCC Part15 Sub Part B	ANSI C63.4 : 2001

1.9 Test Facility

General Information

The sites are constructed in conformance with the requirements of ANSI C63.4 and CISPR 22, 16-1, 16-2.

This EMC Testing Lab. is accredited by Korea Laboratory Accreditation Scheme(KOLAS) which signed the International Laboratory Accreditation Cooperation (ILAC) Mutual Recognition Arrangement (MRA) for the above test item(s) and test method(s).

This Lab. is operated as testing laboratory in accordance with the requirements of ISO/IEC 17025:1998.

Accreditation and Listing



Uncertainty

(According to NAMAS Pub.NIS81)

Samsung IT EMC Test Lab.

Disturbance voltage at Mains : $\pm 1.9\text{dB}$

Radiated disturbance Bi-Log Antenna : $\pm 5.1\text{dB}$

2. Summary of Test Results

Result : PASS

The equipment under test(EUT) has been found to comply with the applied standards.

Section of the Product Standard		Applied Standard	Result
Electromagnetic Emission Test			
3.1	Conducted Emission	Fcc Part 15 Sub. B	Complied
3.2	Radiated Emission	Fcc Part 15 Sub. B	Complied

3.1 Conducted Emission

Test Information	
Test Engineer	Young Hun, Cheong
Test Date	July 02, 2004
Climate Condition	Ambient Temperature :25 Relative Humidity : 58%
	Atmospheric Pressure 1004mbar
Test Place	Shield Room

Test Equipments

Equipment	Model Name	Manufacturer	Serial No.	Calibration	
				Next Date	Interval
LISN	3810/2NM	R&S	2251	2005-02-12	12
EMI TEST RECEIVER	ESCS30	R&S	830986/004	2005-02-12	12
LISN	ESH3-Z5	R&S	831887/004	2004-10-01	12

Measurement Results	Passed The Measured emissions of the EUT have found to be below the specified limits.
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Test Data & Graph

The Initial step in collecting conducted data was to perform a peak and average scan over the measurement range using a receiver

The find data represents worst-case emissions.

* QP : Quasi-peak, AV: Average

* Result = Meter Reading(QP or AV) + Total Loss(LISN Insertion loss + Cable loss)

* Margin = Limit – Result

1. - TEST DATA & GRAPH

1) Average Table

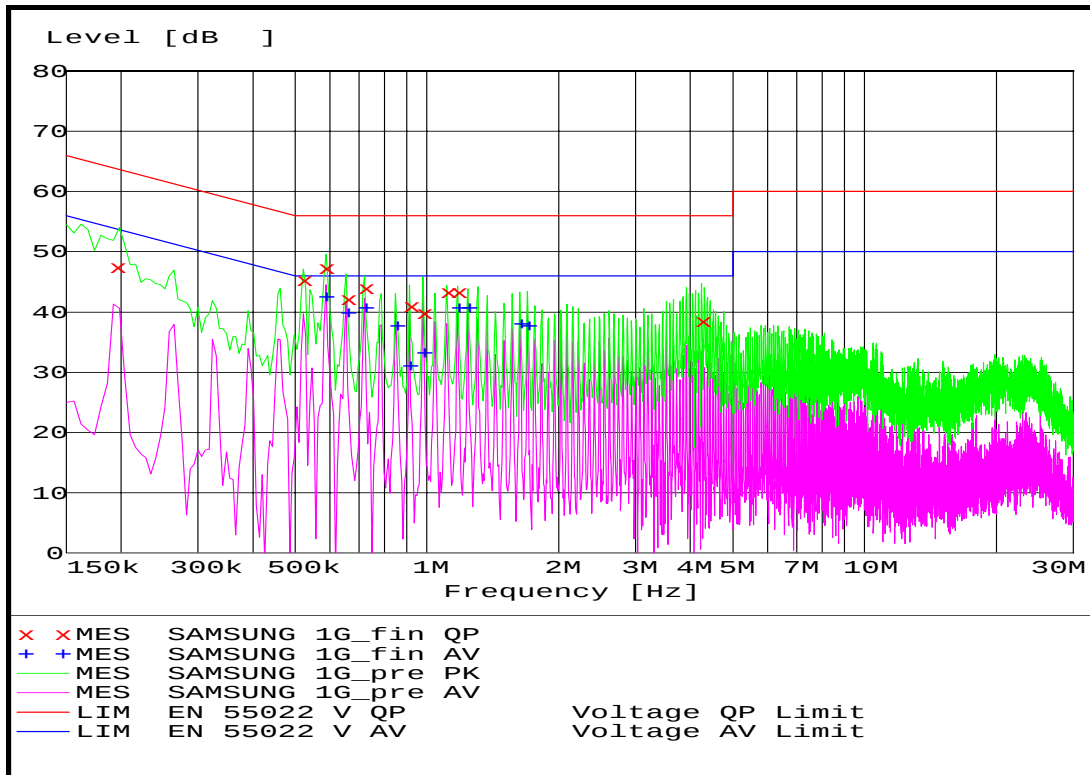
Frequency	Result	Total Loss	Phase	Limit	Margin
[MHz]	[dBuV]	[dB]		[dBuV]	[dB]
0.585	42.40	0.60	L1	46.00	3.6
0.655	39.70	0.50	L1	46.00	6.3
0.720	40.60	0.50	L1	46.00	5.4
0.850	37.70	0.50	N	46.00	8.3
0.910	30.90	0.50	L1	46.00	15.1
0.980	33.10	0.60	L1	46.00	12.9
1.175	40.70	0.60	L1	46.00	5.3
1.240	40.60	0.60	L1	46.00	5.4
1.630	37.90	0.60	L1	46.00	8.1
1.695	37.70	0.60	L1	46.00	8.3

2) Quasi Peak Table

Frequency	Result	Total Loss	Phase	Limit	Margin
[MHz]	[dBuV]	[dB]		[dBuV]	[dB]
0.195	47.50	0.60	N	64.00	16.3
0.520	45.20	0.60	N	56.00	10.8
0.585	47.20	0.60	L1	56.00	8.8
0.655	42.10	0.50	L1	56.00	13.9
0.720	43.90	0.50	L1	56.00	12.1
0.915	40.90	0.50	L1	56.00	15.1
0.980	39.80	0.60	N	56.00	16.2
1.110	43.20	0.60	L1	56.00	12.8
1.175	43.20	0.60	L1	56.00	12.8
4.245	38.50	0.80	L1	56.00	17.5

3) Graph

Level [dBuV]



3.2 Radiated Emission

Test Information	
Test Engineer	Young Hun, Cheong
Test Date	June 30, 2004
Climate Condition	Ambient Temperature : 20 Relative Humidity : 42%
	Atmospheric Pressure 999 mbar
Test Place	10m RF Semi Anechoic Chamber

Test Equipments

Equipment	Model Name	Manufacturer	Serial No.	Calibration	
				Next Date	Interval
Turn Table	DT430	HD	430/691/01	N/A	N/A
Antenna Mast	MA240	HD	240/678 BJ:01	N/A	N/A
Controller	HD100	HD	100/723	N/A	N/A
BILOG Antenna	CBL6112B	Schaffner	2805	2005-03-12	12
Test Receiver	ESI26	R&S	100010	2005-03-16	12

Measurement Results	Pass No Operation errors were detected during or after the applied test.
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Test Data & Graph

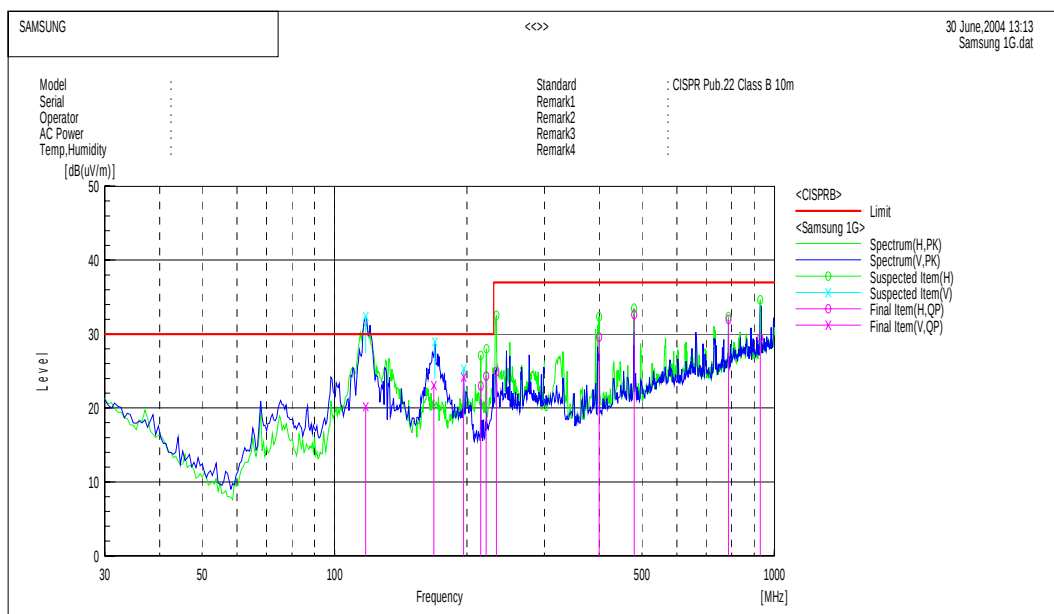
The initial step in collecting radiated data was to perform a peak scan over the measurement range using a receiver. All modes of operation were investigated and the worst-case emission are reported

The minimum margin to the limit is as follows:

All other emission are non-significant.

- * Receiving Antenna Mode : Horizontal, Vertical
- * Test distance : 10m (Semi-Anechoic Chamber)
- * Result = Meter Reading + Total Loss(Antenna factor + Cable loss)
- * Margin = Limit – Result

1) TEST DATA & GRAPH



Final Result

No.	Frequency [MHz]	(P)	S.C	Reading QP [dB(μV)]	c.f [dB(1/m)]	Result QP [dB(μV/m)]	Limit [dB(μV/m)]	Margin QP [dB]	Height [cm]	Angle [deg]	Remark
1	117.663	V	S	27.2	-7.0	20.2	30.0	9.8	138.0	286.0	
2	168.190	V	S	32.9	-9.8	23.1	30.0	6.9	115.0	195.0	
3	196.607	V	S	34.4	-10.2	24.2	30.0	5.8	106.0	202.0	
4	215.026	H	S	32.5	-9.5	23.0	30.0	7.0	378.0	138.0	
5	221.167	H	S	33.4	-9.1	24.3	30.0	5.7	386.0	310.0	
6	233.482	H	S	33.1	-8.1	25.0	37.0	12.0	379.0	74.0	
7	399.550	H	S	31.9	-2.3	29.6	37.0	7.4	223.0	67.0	
8	480.085	H	S	33.2	-0.5	32.7	37.0	4.3	207.0	5.0	
9	786.444	H	S	27.7	4.3	32.0	37.0	5.0	113.0	267.0	
10	929.165	H	S	23.5	6.0	29.5	37.0	7.5	108.0	286.0	

4. Appendix

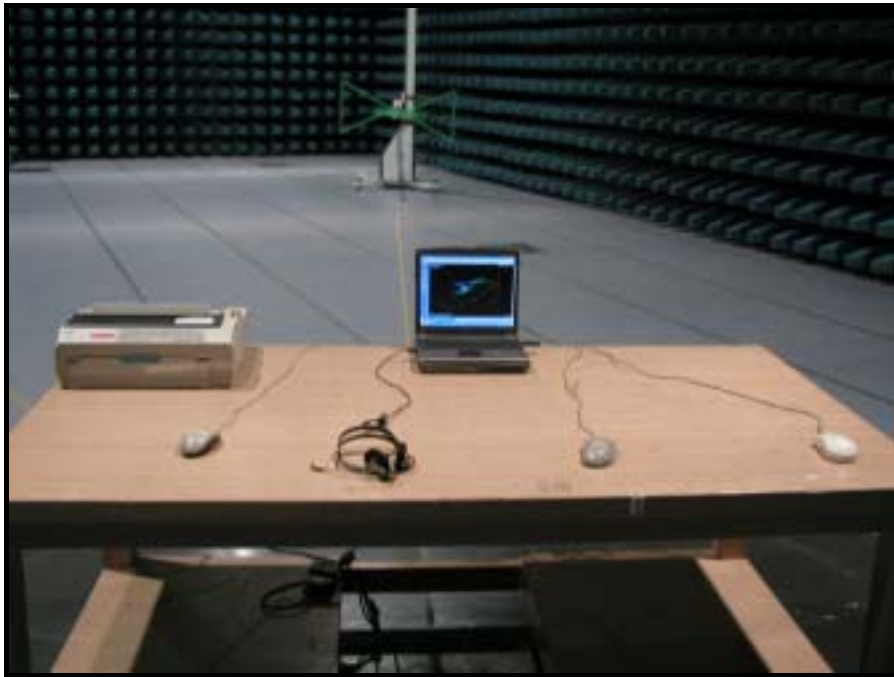
4.1 Test Photography



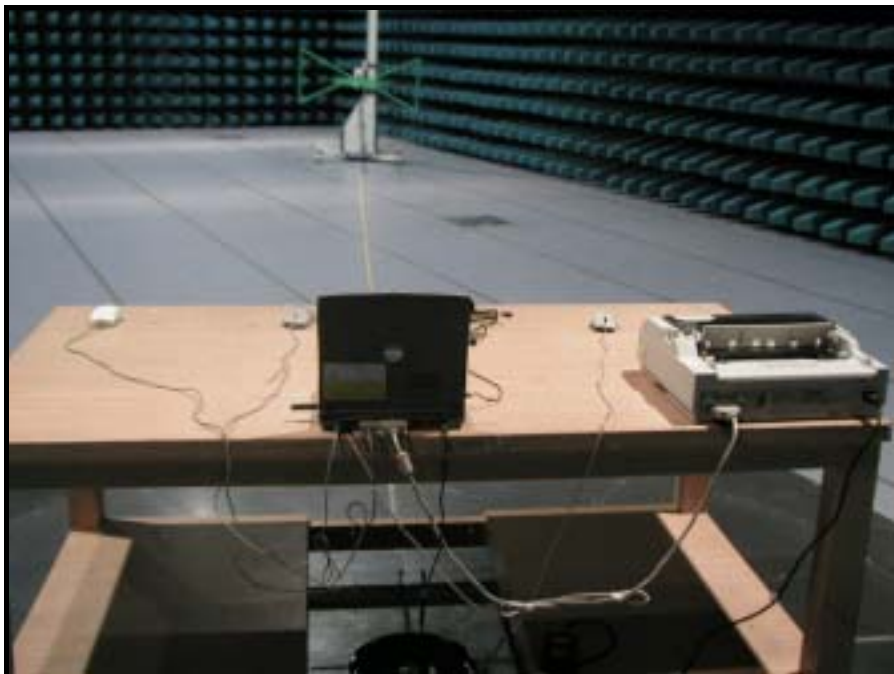
Pic. 1 Conducted Emission (Front)



Pic. 2 Conducted Emission (Rear)



Pic. 3 Radiated Emission (Front)



Pic. 4 Radiated Emission (Rear)

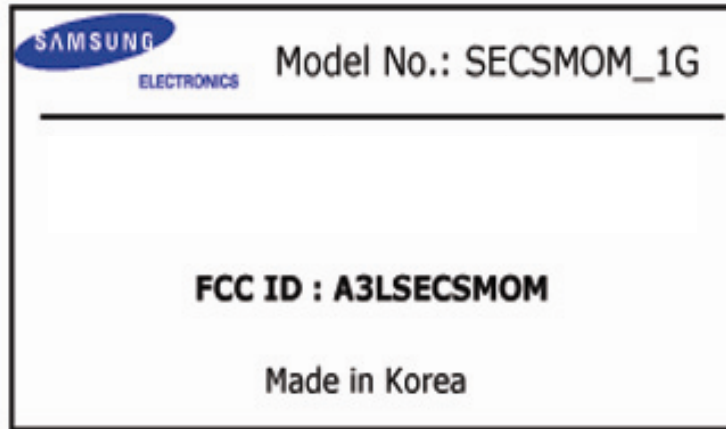
4.2 EUT Photography



Pic. 5 EUT (Front)



Pic. 6 EUT (Rear)



Pic. 7 Label